



# SANYO Semiconductors

## DATA SHEET

# 2SC6094

NPN Epitaxial Planar Silicon Transistor

## High-Current Switching Applications

### Applications

- DC / DC converter, relay drivers, lamp drivers, motor drivers, inverter.

### Features

- Adoption of FBET, MBIT process.
- High current capacitance.
- Low collector-to-emitter saturation voltage.
- High-speed switching.
- High allowable power dissipation.

### Specifications

#### Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Collector-to-Base Voltage	V <sub>CB0</sub>		100	V
Collector-to-Emitter Voltage	V <sub>CES</sub>		100	V
Collector-to-Emitter Voltage	V <sub>CEO</sub>		60	V
Emitter-to-Base Voltage	V <sub>EBO</sub>		6.5	V
Collector Current	I <sub>C</sub>		3	A
Collector Current (Pulse)	I <sub>CP</sub>		5	A
Base Current	I <sub>B</sub>		600	mA
Collector Dissipation	P <sub>C</sub>	Mounted on a ceramic board (250mm <sup>2</sup> X0.8mm)	1.3	W
		T <sub>c</sub> =25°C	3.5	W
Junction Temperature	T <sub>j</sub>		150	°C
Storage Temperature	T <sub>stg</sub>		-55 to +150	°C

#### Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
Collector Cutoff Current	I <sub>CB0</sub>	V <sub>CB</sub> =50V, I <sub>E</sub> =0A			1	μA
Emitter Cutoff Current	I <sub>EBO</sub>	V <sub>EB</sub> =4V, I <sub>C</sub> =0A			1	μA
DC Current Gain	h <sub>FE</sub>	V <sub>CE</sub> =2V, I <sub>C</sub> =100mA	300		600	

Marking : QE

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# 2SC6094

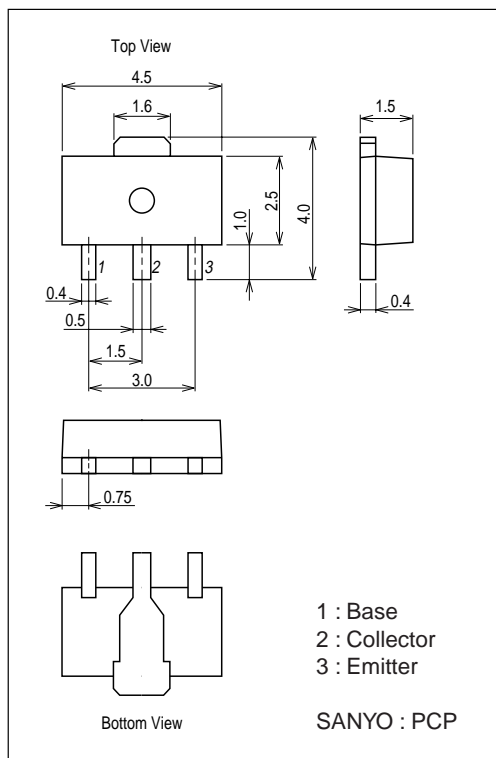
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Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
Gain-Bandwidth Product	$f_T$	$V_{CE}=10V, I_C=500mA$		390		MHz
Output Capacitance	$C_{ob}$	$V_{CB}=10V, f=1MHz$		18		pF
Collector-to-Emitter Saturation Voltage	$V_{CE(sat)1}$	$I_C=1A, I_B=50mA$		90	135	mV
	$V_{CE(sat)2}$	$I_C=1A, I_B=100mA$		80	120	mV
Base-to-Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C=1A, I_B=100mA$		0.84	1.2	V
Collector-to-Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C=10\mu A, I_E=0A$	100			V
Collector-to-Emitter Breakdown Voltage	$V_{(BR)CES}$	$I_C=100\mu A, R_{BE}=0\Omega$	100			V
Collector-to-Emitter Breakdown Voltage	$V_{(BR)CEO}$	$I_C=1mA, R_{BE}=\infty$	60			V
Emitter-to-Base Breakdown Voltage	$V_{(BR)EBO}$	$I_E=10\mu A, I_C=0A$	6.5			V
Turn-ON Time	$t_{on}$	See specified Test Circuit.		35		ns
Storage Time	$t_{stg}$	See specified Test Circuit.		680		ns
Fall Time	$t_f$	See specified Test Circuit.		24		ns

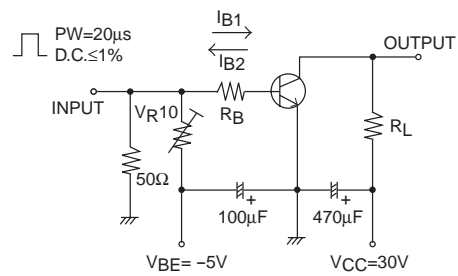
## Package Dimensions

unit : mm

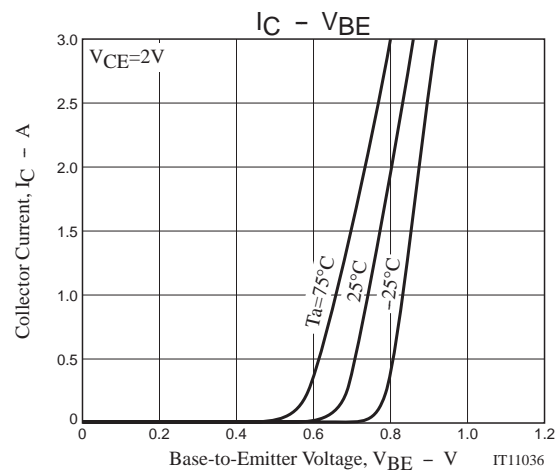
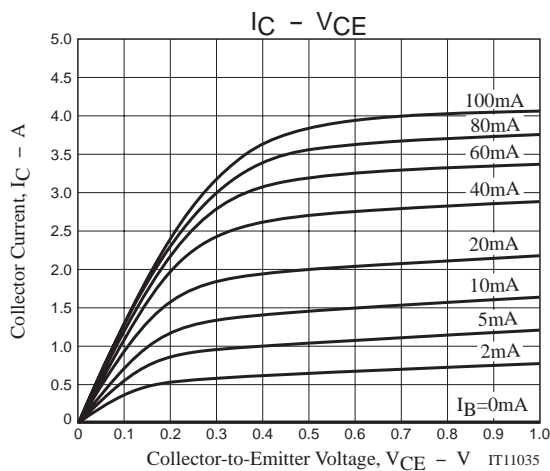
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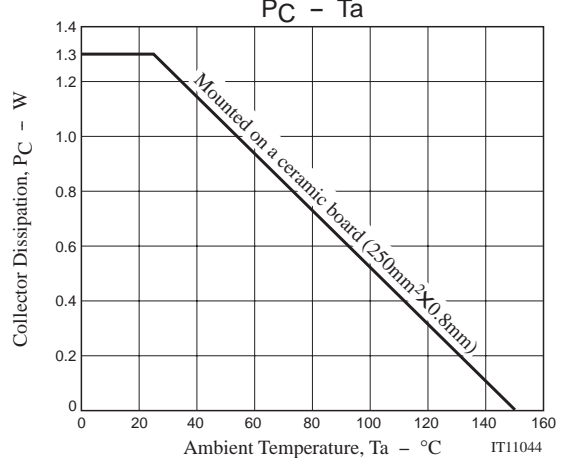
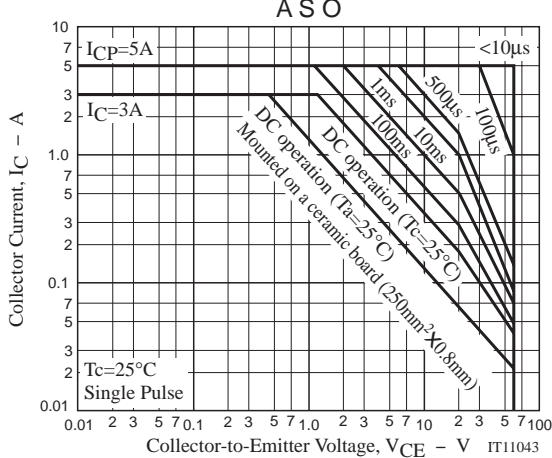
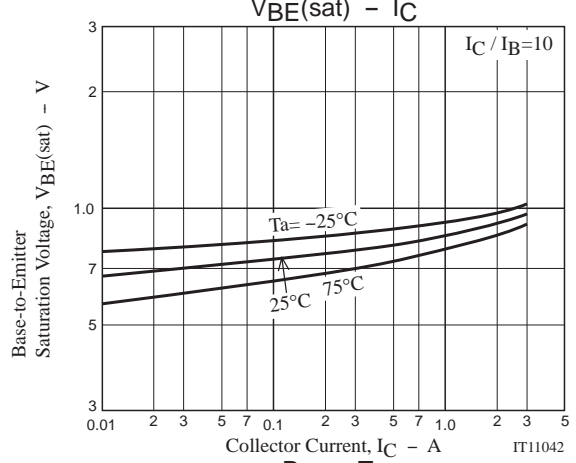
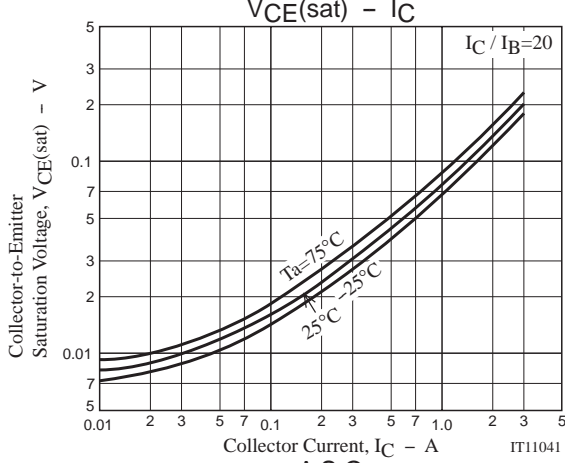
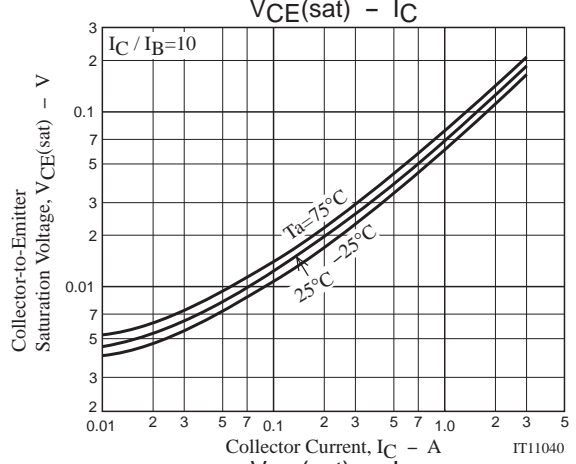
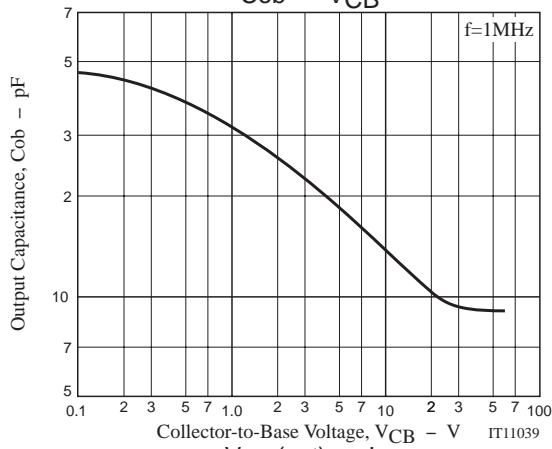
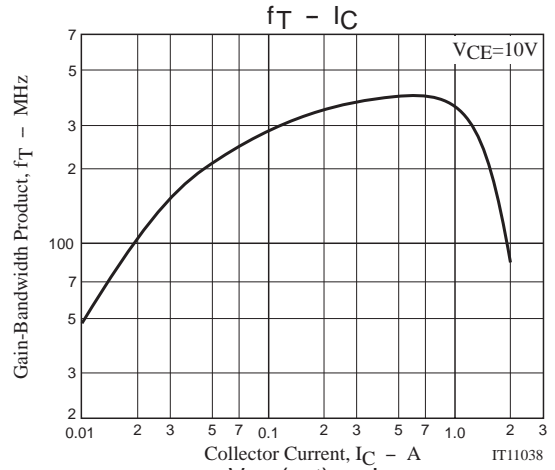
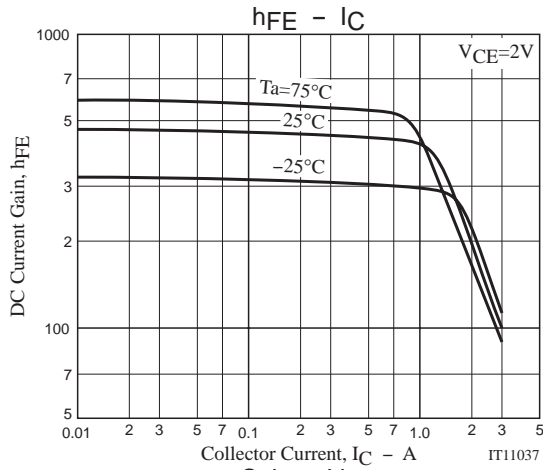


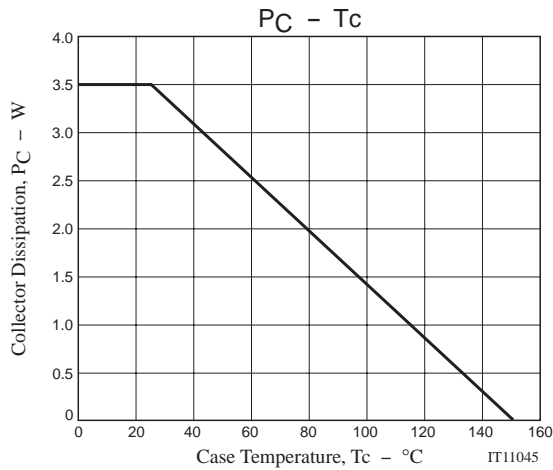
## Switching Time Test Circuit



$$10I_{B1} = -10I_{B2} = I_C = 0.5A$$







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